

OIE
APR 17 2002

SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 211559US2SRDDIV	SERIAL NO. 09/920,936		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Toshiaki WATANABE, et al.			
		FILING DATE August 3, 2001		GROUP 2663			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>Ph</i>	AA	5,162,923	11/10/92	T. YOSHIDA, et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
<i>RECEIVED</i> APR 18 2002 Technology Center 2600							
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO	
<i>Ph</i>	AL	04-239839	08/27/92	JAPAN (with English Abstract)		X	
<i>Ph</i>	AM	04-245833	1992	JAPAN (submitting corr. EP 0 497 452 only)	<i>A65</i>		
<i>Ph</i>	AN	0 497 452	08/05/92	EUROPE			
<i>Ph</i>	AO	01-213067	1989	JAPAN (submitting corr. US 5,162,923 only)	<i>A65</i>		
<i>Ph</i>	AP	07-508380	1995	JAPAN (submitting corr. WO 94/00952 only)	<i>A65</i>		
<i>Ph</i>	AQ	WO 94/00952	01/06/94	WIPO			
<i>Ph</i>	AR	07-162801	06/23/95	JAPAN (with English Abstract)		X	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>Ph</i>	AS	Patent Abstracts of Japan, JP 08-162979, June 21, 1996					
<i>Ph</i>	AT	Patent Abstracts of Japan, JP 57-115043, July 17, 1982					
<i>Ph</i>	AU	Patent Abstracts of Japan, JP 02-062176, March 2, 1990					
<i>Ph</i>	AV	Patent Abstracts of Japan, JP 07-143480, June 2, 1995					
<i>Ph</i>	AW	Patent Abstracts of Japan, JP 02-206292, August 16, 1990					
<i>Ph</i>	AX	Patent Abstracts of Japan, JP 06-086251, March 25, 1994					
<i>Ph</i>	AY	Patent Abstracts of Japan, JP 06-215492, August 5, 1994					
<i>Ph</i>	AZ	Patent Abstracts of Japan, JP 06-205384, July 22, 1994					
Examiner	<i>Panban Phuan</i>			Date Considered	<i>12/1/004</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

LIST OF PRIOR ART CITED BY APPLICANT O I P E (PTO-1449) DEC 31 2003		ATTY. DOCKET NO. P-242	APPLN. SERIAL NO. 09/920,853			
 U.S. PATENT DOCUMENTS		APPLICANT(S) Jae-Hyuk LEE				
		CUSTOMER NO. 34610				
		FILING DATE August 3, 2001	GROUP 2817			
RECEIVED						
JAN 05 2004						
Technology Center 2600						
U.S. PATENT APPLICATION PUBLICATIONS						
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
U.S. PATENT APPLICATIONS						
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
						Yes
<i>Ph</i>	GB 2 283 629 A	05/10/1995	Germany			X
<i>Ph</i>	WO 00/08870	02/17/2000	WIPO			X
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)						
EXAMINER <i>Pantay Munin</i>			DATE CONSIDERED 12/1004			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.